

RoHS

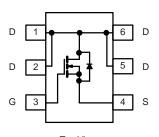
COMPLIANT HALOGEN

FREE

BSL302SN-VB Datasheet

N-Channel 30 V (D-S) MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	R _{DS(on)} (Ω)	I _D (A) ^{a, e}	Q _g (Typ.)			
30	0.023 at V_{GS} = 10 V	6	4.2 nC			
50	0.027 at V _{GS} = 4.5 V	6	4.2 110			



TSOP-6

Top View

FEATURES

- Halogen-free According to IEC 61249-2-21
 Definition
- TrenchFET[®] Power MOSFET
- Low On-Resistance
- 100 % R_g Tested
- Compliant to RoHS Directive 2002/95/EC

APPLICATIONS

DC/DC Converte

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Parameter	Symbol	Limit	Unit		
Drain-Source Voltage	V _{DS}	30	V		
Gate-Source Voltage		V _{GS}	± 20	V	
	T _C = 25 °C		6 ^e		
Continuous Drain Current (T 150 °C)	T _C = 70 °C		6 ^e		
Continuous Drain Current ($T_J = 150 \ ^{\circ}C$)	T _A = 25 °C	I _D	5.5 ^{b, c}		
	T _A = 70 °C		4.4 ^{b, c}	A	
Pulsed Drain Current (t = 300 µs)		I _{DM}	25		
Continuous Source-Drain Diode Current	T _C = 25 °C		2.1		
Continuous Source-Drain Diode Current	T _A = 25 °C	Is –	1.1 ^{b, c}		
	T _C = 25 °C		2.5		
Maximum Power Dissipation	T _C = 70 °C		1.6	W	
	T _A = 25 °C	P _D —	1.3 ^{b, c}	vv	
	T _A = 70 °C	1	0.8 ^{b, c}		
Operating Junction and Storage Temperatur	T _J , T _{stg}	- 55 to 150	°C		
Soldering Recommendations (Peak Tempera		260			

THERMAL RESISTANCE RATINGS Parameter Symbol Typical Maximum Unit Maximum Junction-to-Ambient^{b, d} t ≤ 5 s R_{thJA} 75 100 °C/W Maximum Junction-to-Foot (Drain) Steady State 40 50 R_{thJF}

Notes:

a. Based on $T_C = 25 \ ^{\circ}C$.

b. Surface mounted on 1" x 1" FR4 board.

c. t = 5 s.

d. Maximum under steady state conditions is 166 °C/W.

e. Package limited.

Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static						
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 V, I_{D} = 250 \mu A$	30			V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$			30		mV/°C
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA		- 4.8		
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_{D} = 250 \ \mu A$	0.5		1.5	V
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 V, V_{GS} = \pm 20 V$			± 100	nA
-	I _{DSS}	$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}$			1	μA
Zero Gate Voltage Drain Current		V _{DS} = 30 V, V _{GS} = 0 V, T _J = 70 °C			10	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \le 5 \text{ V}, \text{ V}_{GS} = 10 \text{ V}$	20			А
		V _{GS} = 10 V, I _D = 5.5 A		0.023		Ω
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 4.5 \text{ V}, I_D = 5 \text{ A}$		0.027		
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 5.5 A		24		S
Dynamic ^b				1	L	
Input Capacitance	C _{iss}			424		pF
Output Capacitance	C _{oss}	V _{DS} = 15 V, V _{GS} = 0 V, f = 1 MHz		100		
Reverse Transfer Capacitance	C _{rss}			42		
·		V _{DS} = 15 V, V _{GS} = 10 V, I _D = 5.5 A		8.2	13	nC
Total Gate Charge	Qg			4.2	7	
Gate-Source Charge	Q _{gs}	V_{DS} = 15 V, V_{GS} = 4.5 V, I_{D} = 5.5 A		1.4		
Gate-Drain Charge	Q _{gd}			1.4		
Gate Resistance	R _g	f = 1 MHz	2.5	12.6	25.2	Ω
Turn-On Delay Time	t _{d(on)}			6	12	
Rise Time	t _r	$V_{DD} = 15 \text{ V}, \text{ R}_1 = 3.4 \Omega$		20	30	- ns
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 4.4 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$		14	21	
Fall Time	t _f	-		10	20	
Turn-On Delay Time	t _{d(on)}			3	6	
Rise Time	t _r	$V_{DD} = 15 \text{ V}, \text{ R}_1 = 3.4 \Omega$		11	20	
Turn-Off Delay Time	t _{d(off)}	$I_D \approx 4.4 \text{ A}, V_{GEN} = 10 \text{ V}, \text{ R}_g = 1 \Omega$		20	30	
Fall Time	t _f	-		7	14	
Drain-Source Body Diode Characteristi	cs			1	L	
Continuous Source-Drain Diode Current	ا _S	T _C = 25 °C			2.1	
Pulse Diode Forward Current	I _{SM}				25	A
Body Diode Voltage	V _{SD}	$I_{S} = 4.4 \text{ A}, V_{GS} = 0 \text{ V}$		0.82	1.2	V
Body Diode Reverse Recovery Time	t _{rr}			13	20	ns
Body Diode Reverse Recovery Charge	Q _{rr}			6	12	nC
Reverse Recovery Fall Time	t _a	$I_F = 4.4 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, \text{ T}_J = 25 \text{ °C}$		8		
Reverse Recovery Rise Time	t _b			5		ns

Notes:

a. Pulse test; pulse width \leq 300 µs, duty cycle \leq 2 %. b. Guaranteed by design, not subject to production testing.

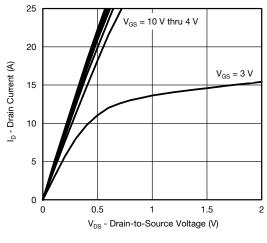
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

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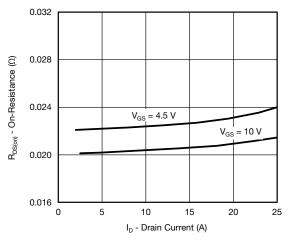
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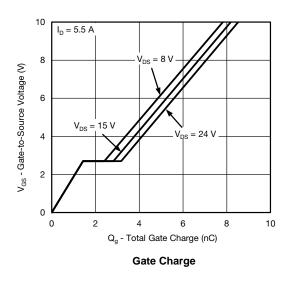
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

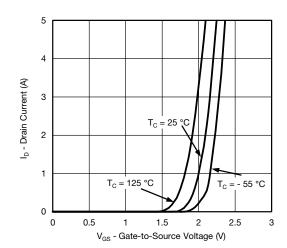




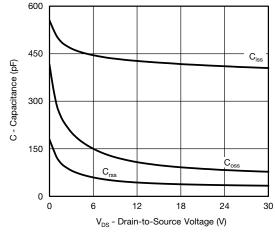


On-Resistance vs. Drain Current and Gate Voltage

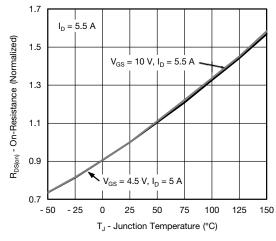




Transfer Characteristics

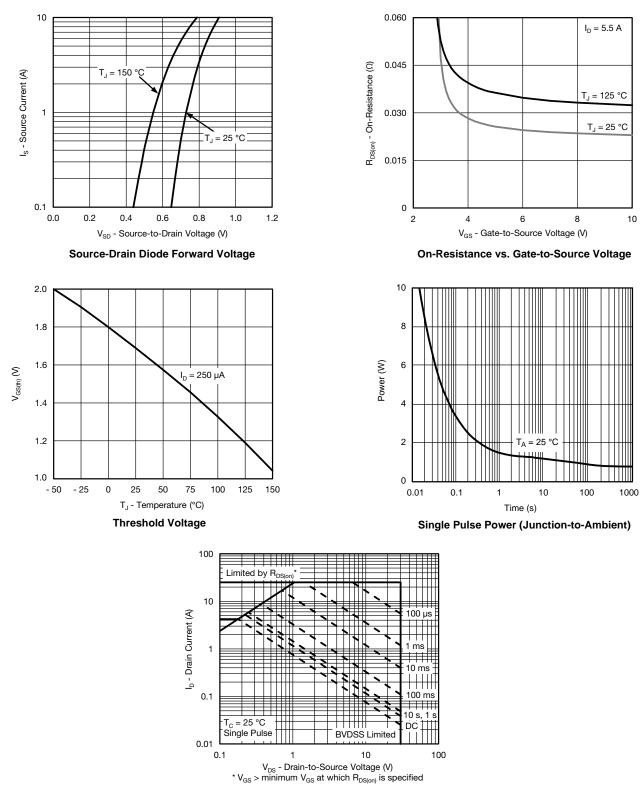






On-Resistance vs. Junction Temperature



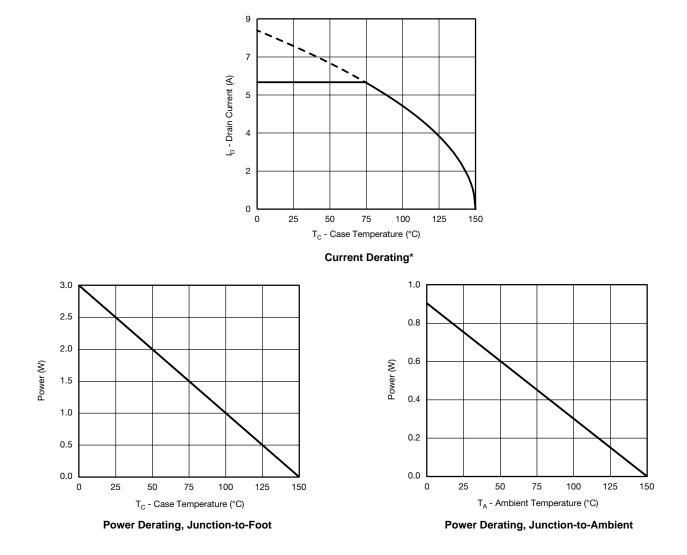


TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)





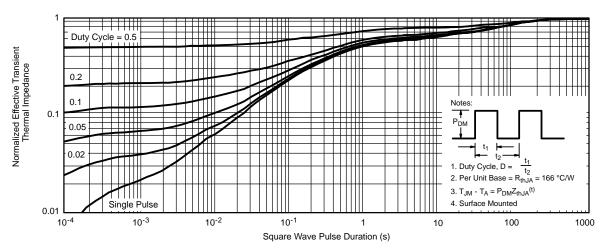
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



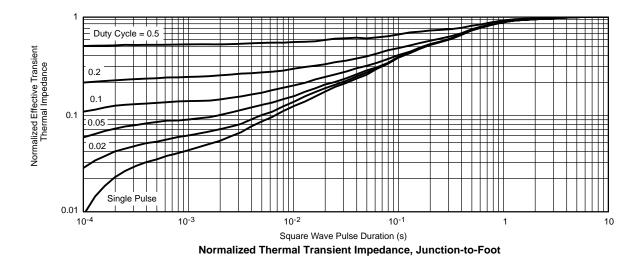
* The power dissipation P_D is based on $T_{J(max.)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.







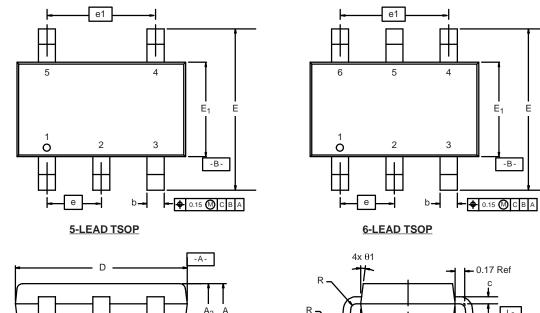
Normalized Thermal Transient Impedance, Junction-to-Ambient

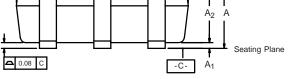


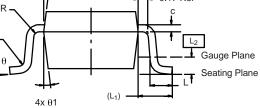


TSOP: 5/6-LEAD

JEDEC Part Number: MO-193C



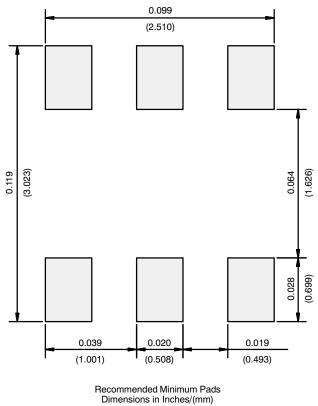




	MILLIMETERS			INCHES			
Dim	Min	Nom	Max	Min	Nom	Max	
Α	0.91	-	1.10	0.036	-	0.043	
A ₁	0.01	-	0.10	0.0004	-	0.004	
A ₂	0.90	-	1.00	0.035	0.038	0.039	
b	0.30	0.32	0.45	0.012	0.013	0.018	
С	0.10	0.15	0.20	0.004	0.006	0.008	
D	2.95	3.05	3.10	0.116	0.120	0.122	
Е	2.70	2.85	2.98	0.106	0.112	0.117	
E ₁	1.55	1.65	1.70	0.061	0.065	0.067	
е	0.95 BSC			0.0374 BSC			
e ₁	1.80	1.90	2.00	0.071	0.075	0.079	
L	0.32	-	0.50	0.012	-	0.020	
L ₁	0.60 Ref			0.024 Ref			
L ₂	0.25 BSC			0.010 BSC			
R	0.10	-	-	0.004	-	-	
θ	0°	4°	8°	0°	4°	8°	
θ 1	7° Nom			7° Nom			
ECN: C-06593-Rev. I, 18-Dec-06 DWG: 5540							



RECOMMENDED MINIMUM PADS FOR TSOP-6





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